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Attorney Docket No. 49481 (70551)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANT(S): M. HATANAKA et al. **EXAMINER:** S. Turner
U.S.S.N.: 09/471,829 **ART UNIT:** 2877
FILED: December 23, 1999
TITLE: APPARATUS AND METHOD FOR MEASURING THE
(as amended herein) THICKNESS OF A THIN FILM VIA THE INTENSITY OF
REFLECTED LIGHT

CERTIFICATE OF MAILING

I hereby certify that this paper (along with any paper referred to as being attached, enclosed or accompanying) is being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to: **Mail Stop AF**, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on May 28, 2004.

By: 
Lee Dunkle

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Mail Stop AF
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

AMENDMENT AND RESPONSE TO OFFICE ACTION
PURSUANT TO 37 C.F.R. §1.116

Sir:

In response to the office action dated April 1, 2004, please consider the following amendments and remarks in favor of the allowance of claims 1 and 3-20 of the above-referenced patent application. Please note that the amendments to the specification and claims commence, respectively, on page 2 and page 3, and the accompanying remarks commence on page 15.